

**Search Notes**

Application/Control No.

10/805,592

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

ANDERSEN ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	10	11/8/2005	HN
330	251	11/8/2005	HN
330	207A	11/8/2005	HN
330	195	11/8/2005	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
CLASSES	ABOVE	11/8/2005	HN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB;USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	11/8/2005	HN
MOTTOLA STEVEN J	11/8/2005	HN